Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/617,171	JEONG, KI-TAG
Examiner	Art Unit
Tianjie Chen	2627

SEARCHED					
Class	Subclass	Date	Examiner		
Updated		6/15/2006	TJ		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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